

## PNP Transistor Bare Die - BC558

Rev 1.0 08/01/19

### General purpose medium power amplifier or switch in bare die form

Complement to NPN BC548

#### Features:

- High Collector Current
- Very low saturation voltage
- Well suited for low noise amplifier applications
- High Reliability Gold Back Metal
- High Reliability tested grades for Military + Space

#### Ordering Information:

The following part suffixes apply:

- No suffix MIL-STD-750 /2072 Visual Inspection
- "H" MIL-STD-750 /2072 Visual Inspection+ MIL-STD-38534 Class H LAT
- "K" MIL-STD-750 /2072 Visual Inspection+ MIL-STD-38534 Class K LAT

LAT = Lot Acceptance Test.

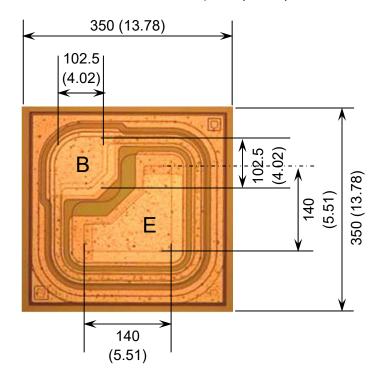
For further information on LAT process flows see below.

www.siliconsupplies.com\quality\bare-die-lot-qualification

#### **Supply Formats:**

- Default Die in Waffle Pack (400 per tray capacity)
- Sawn Wafer on Tape Specific request
- Unsawn Wafer Specific request
- With additional electrical selection Specific request
- Sawn as pairs or adjacent pair pick Specific request

#### Die Dimensions in µm (mils)



**E** = EMITTER **B** = BASE

**DIE BACK = COLLECTOR** 

#### **Mechanical Specification**

Die Size	350 x 350	μm		
(Excluding Saw Street)	13.78 x 13.78	mils		
D D 10:	102.5 x 102.5			
Base Pad Size	4.02 x 4.02	μm		
F '''	96 x 96	mils		
Emitter Pad Size	5.51 x 5.51			
B: TI: I	230 (±15)	μm		
Die Thickness	9.06 (±0.59)	mils		
Top Metal Composition	Al - 1.3µm			
Back Metal Composition	AuAs - 0.9µm			





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### Absolute Maximum Ratings T<sub>A</sub> = 25°C unless otherwise stated

PARAMETER	SYMBOL	VALUE	UNIT
Collector-Base Voltage	V <sub>CBO</sub>	-30	V
Collector-Emitter Voltage	V <sub>CEO</sub>	-30	V
Emitter-Base Voltage	V <sub>EBO</sub>	-5	V
Collector Current	Ic	-100	mA
Junction Temperature	TJ	150	°C
Storage Temperature	T <sub>stg</sub>	-55 to 150	°C

#### Electrical Characteristics T<sub>A</sub> = 25°C unless otherwise stated

PARAMETER	SYMBOL	CONDITIONS		MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS							
Collector-Base Breakdown Voltage	V <sub>(BR)CBO</sub>	$I_{C} = -10\mu A, I_{E} = 0$		-80	-	-	V
Collector-Emitter Breakdown Voltage	V <sub>(BR)CEO</sub>	$I_{C} = -10 \text{mA}, I_{B} = 0$		-65	-	-	V
Emitter-Base Breakdown Voltage	$V_{(BR)EBO}$	$I_{E} = -10\mu A, I_{C} = 0$		-5	-	-	V
Collector Cut-off Current	I <sub>CBO</sub>	$V_{CB} = -30V, I_{E} = 0$		-	-	-15	nA
ON CHARACTERISTICS							
Forward-Current Transfer Ratio <sup>1</sup>	h <sub>FE</sub>	BC558	V <sub>CE</sub> = -5V, I <sub>C</sub> = -2mA	110	-	800	-
		BC558A		110	-	220	-
		BC558B		200	-	450	-
		BC558C		420	-	800	-
Collector-Emitter Saturation Voltage	V <sub>CE(sat)</sub>	$I_{\rm C}$ = -10mA, $I_{\rm B}$ = -0.5mA		-	-90	-300	mV
		$I_C = -100 \text{mA}, I_B = -5 \text{mA}$		-	-250	-650	mV
Base-Emitter Saturation Voltage	V <sub>BE(sat)</sub>	$I_{C} = -10 \text{mA}, I_{B} = -0.5 \text{mA}$		-	-700	-	mV
		$I_{C} = -100 \text{mA}, I_{B} = -5 \text{mA}$		-	-900	-	mV
Base-Emitter On Voltage	V <sub>BE(on)</sub>	$I_C = -2A, V_{CE} = -5V$		-600	-660	-750	mV
		$I_{C} = -10A$ , $V_{CE} = -5V$		-	-	-800	mV
SMALL SIGNAL CHARACTERISTICS	!						
		V <sub>CE</sub> = -5V, I	c = -10mA, f = 10 MHz	-	150	-	MHz
Output Capacitance	C <sub>obo</sub>	$V_{CB} = -10V, I_E = 0, f = 1MHz$		-	-	6	pF
Noise Figure	NF	$V_{CE}$ = -5V, $I_C$ = -200 $\mu$ A, $R_G$ = 2k $\Omega$ , f = 1kHz		-	2	10	dB

Note 1: Pulse Test: Pulse Width ≤ 300 µs, Duty Cycle ≤ 2%

DISCLAIMER: The information given in this document shall in no event be regarded as a guarantee of conditions or characteristics. With respect to any examples or hints given herein, any typical values stated herein and/or any information regarding the application of the device, Silicon Supplies Ltd hereby disclaims any and all warranties and liabilities of any kind.

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Note 2: Not production testing in die form. Characterized by chip design and tested in package